

AMENDMENTS TO THE CLAIMS

The claims in this listing will replace all prior versions, and listings, of claims in the application:

1. (Currently Amended) An image sensor test system configured to bring input/output terminals of an image sensor into contact with a contact of a test head, the image test system configured to emit light to a light receiving surface of the image sensor from a light source and, while doing so, inputting/outputting electrical signals between the contact of the test head and the image sensor so as to test the optical properties of the image sensor, the image sensor test system comprising:

a pre-test sensor stacker configured to store image sensors before testing;

a first inverter configured to invert an image sensor supplied from the pre-test sensor stacker;

a contact arm configured to pick up and move the inverted image sensor inverted by the first inverter, the contact arm being configured to bring input/output terminals of the inverted image sensor into electrical contact with a contact of the test head;

an attachment portion configured to attach the light source and the test head to the image sensor test system so as to place the light source and the test head beneath the image sensor;

a second inverter configured to invert an image sensor after testing; and

a plurality of post-test sensor stackers configured to store tested image sensors inverted by the second inverter.

2. (Previously Presented) The image sensor test system as set forth in claim 1, wherein each of the first and second inverters are configured to simultaneously invert at least two image sensors.

3. (Previously Presented) The image sensor test system as set forth in claim 1, wherein each of the first and second inverters comprises at least a first holder configured to hold an image sensor and a rotation mechanism configured to rotate the first holder.

4. (Previously Presented) The image sensor test system as set forth in claim 3, wherein the first holder comprises a suction nozzle configured to hold an image sensor by applying suction.

5. (Previously Presented) The image sensor test system as set forth in claim 4, wherein the first holder is exchangeable with another first holder having a suction nozzle different from the suction nozzle of the first holder, the another first holder corresponding to a size or shape of an image sensor.

6. (Previously Presented) An image sensor test system configured to bring input/output terminals of an image sensor into contact with a contact of a test head, the image test system configured to emit light to a light receiving surface of the image sensor from a light source and, while doing so, inputting/outputting electrical signals between the contact of the test head and the image sensor so as to test the optical properties of the image sensor, the image sensor test system comprising:

a pre-test sensor stacker configured to store image sensors before testing;

a first inverter configured to invert an image sensor supplied from the pre-test sensor stacker;

a contact arm configured to pick up and move the inverted image sensor inverted by the first inverter, the contact arm being configured to bring input/output terminals of the inverted image sensor into electrical contact with a contact of the test head;

a second inverter configured to invert an image sensor after testing; and

a plurality of post-test sensor stackers configured to store tested image sensors inverted by the second inverter,

wherein each of the first and second inverters comprises at least a first holder configured to hold an image sensor and a rotation mechanism configured to rotate the first holder, and

wherein the rotation mechanism comprises a pinion gear which supports the first holder and a rack gear which intermeshes with the pinion gear and converts linear force supplied to the rack gear to rotational force so as to rotate the first holder.

7. -9. (Canceled)

10. (Currently Amended) An image sensor test system configured to bring input/output terminals of an image sensor into contact with a contact of a test head, the image test system configured to emit light to a light receiving surface of the image sensor from a light source and, while doing so, inputting/outputting electrical signals between

the contact of the test head and the image sensor so as to test the optical properties of the image sensor, the image sensor test system comprising:

a pre-test sensor stacker configured to store image sensors before testing;

a first inverter configured to invert an image sensor supplied from the pre-test sensor stacker;

a contact arm configured to pick up and move the inverted image sensor inverted by the first inverter, the contact arm being configured to bring input/output terminals of the inverted image sensor into electrical contact with a contact of the test head;

a second inverter configured to invert an image sensor after testing; and

a plurality of post-test sensor stackers configured to store tested image sensors inverted by the second inverter;

an imaging device configured to obtain an image of a back surface of the image sensor after being inverted by the first inverter and before being supplied to the test head;
and

~~The image sensor test system as set forth in claim 9, further comprising~~ a judging device configured to judge an emission pattern of light emitted from the light source and an input pattern of electrical signals input from a contact of the test head based on image information obtained by the imaging device.

11. (Currently Amended) The image sensor test system as set forth in ~~claim 9~~ claim 10, further comprising a selector configured to select a tested sensor stacker to unload the image sensor from among the plurality of tested sensor stackers based on

device type information obtained by the imaging device and classification information of the test results.

12. -14. (Canceled)

15. (Currently Amended) A test method for an image sensor which brings input/output terminals of an image sensor into contact with a contact of a test head, emits light to a light receiving surface of the image sensor from a light source, and, while doing so, inputs and outputs electrical signals between the contact of the test head and the image sensor so as to test the optical properties of the image sensor, the test method comprising:

inverting an image sensor before testing,

obtaining an image of an image sensor to obtain device type information before testing the inverted image sensor,

~~The test method for an image sensor as set forth in claim 14, further comprising~~
judging an emission pattern of light emitted from the light source and an input pattern of electrical signals input from a contact of the test head based on the device type information obtained in obtaining the image of the image sensor,

bringing the inverted image sensor into electrical contact with a contact of the test head and emitting light on a light receiving surface of the inverted image sensor from a light source to test the optical properties of the inverted image sensor, and

inverting the tested inverted image sensor,

in testing the inverted image sensor, emitting light to the light receiving surface of the image sensor in accordance with the emission pattern, and inputting and outputting electrical signals between the contact of the test head and the image sensor in accordance with the input pattern.

16. (Currently Amended) The test method for an image sensor as set forth in ~~claim 14~~ claim 15, further comprising sorting tested image sensors based on the device type information obtained in ~~testing~~ obtaining the image of the inverted image sensor and classification information of the test results.

17. (Canceled)

18. (Canceled)